

## 9-10 GHz 18 Watt GaN Power Amplifier

### **Product Overview**

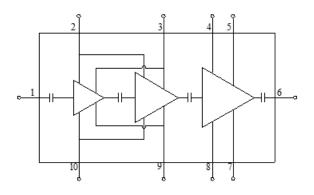
Qorvo's TGA2624 is an x-band, high power MMIC amplifier fabricated on Qorvo's production 0.25 um GaN on SiC process (QGaN25). The TGA2624 operates from 9 – 10 GHz and provides a superior combination of power, gain, and efficiency.

Achieving 18 W of saturated output power with 27.5 dB of large signal gain and greater than 40% power-added efficiency, the TGA2624 provides the level of performance demanded by today's system architectures.

Depending on the system requirements, the TGA2624 can support cost saving initiatives on existing systems while supporting next generation systems with increased performance.

Lead-free and RoHS compliant.

## **Functional Block Diagram**





### **Key Features**

Frequency Range: 9 – 10 GHz
 P<sub>SAT</sub>: 42.5 dBm (PIN = 15 dBm)

• P1dB: > 38dBm

PAE: > 40% (PIN = 15 dBm)
 Large Signal Gain: 27.5 dB

• Small Signal Gain: > 35 dB

• Return Loss: > 11 dB

• Bias:  $V_D = 28 \text{ V}$ ,  $I_{DQ} = 365 \text{ mA}$ 

• Pulsed  $V_{D:}PW = 100 \text{ us and DC} = 10\%$ 

• Die Dimensions: 5.0 x 2.62 x 0.10 mm

Performance is typical across frequency. Please reference electrical specification table and data plots for more details.

## **Applications**

Weather and Marine Radar

## **Ordering Information**

Part No.	Description		
TGA2624	9-10 GHz 18 Watt GaN Amplifier (10 Pcs.)		
TGA2624EVB	Evaluation Board for TGA2624		





## **Absolute Maximum Ratings**

Parameter	Value / Range		
Drain Voltage (V <sub>D</sub> )	40 V		
Gate Voltage Range (V <sub>G</sub> )	-5 to 0 V		
Drain Current (I <sub>D1-2</sub> )	1.6 A		
Drain Current (I <sub>D3</sub> )	2.1 A		
Gate Current (I <sub>G1-2</sub> )	See plot, page 9		
Gate Current (I <sub>G3</sub> )	See plot, page 9		
Power Dissipation (P <sub>DISS</sub> ), 85°C	49 W		
Input Power ( $P_{IN}$ ), $CW$ , $50\Omega$ , $V_D = 28V$ , $85^{\circ}C$	25 dBm		
Input Power (P <sub>IN</sub> ), CW, VSWR 6:1, $V_D = 28V$ , 85°C	19 dBm		
Soldering Temperature (30 s, max.)	320 °C		
Storage Temperature	−55 to +150 °C		

Operation of this device outside the parameter ranges given above may cause permanent damage. These are stress ratings only, and functional operation of the device at these conditions is not implied.

## **Recommended Operating Conditions**

Parameter	Value / Range		
Drain Voltage (V <sub>D</sub> )	28 V		
Drain Current (I <sub>DQ</sub> )	365 mA		
Operating Temperature	−40 to +85 °C		

Electrical specifications are measured at specified test conditions. Specifications are not guaranteed over all recommended operating conditions.

## **Electrical Specifications**

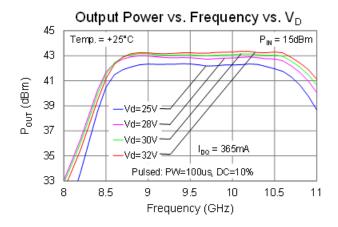
Parameter	Min	Тур	Max	Units
Operational Frequency Range	9		10	GHz
Small Signal Gain		>35		dB
Input Return Loss		>11		dB
Output Return Loss		>11		dB
Output Power (Pin = 15dBm)	41.5	>42.5		dBm
Power Added Efficiency (Pin = 15dBm)	37	>40		%
Power @ 1dB Compression (P1dB)		>38		dBm
Small Signal Gain Temperature Coefficient		-0.06		dB/°C
Recommended Operating Voltage:	20	28	32	V

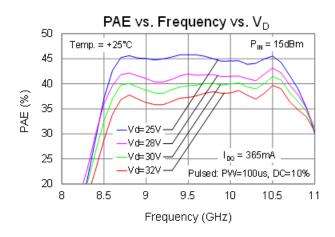
Test conditions unless otherwise noted: 25  $^{\circ}$ C,  $V_D$  = 28 V,  $I_{DQ}$  = 365 mA, Pulsed  $V_{D:}$  PW = 100 us, DC = 10%

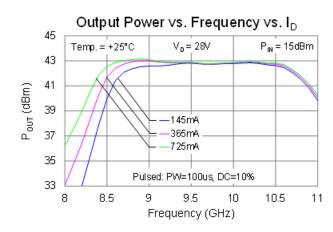


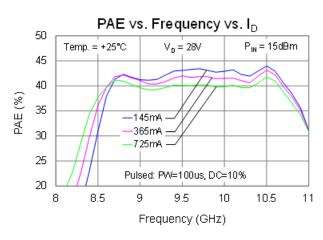
## Performance Plots - Large Signal (Pulsed)

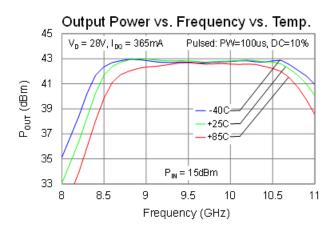
Test conditions unless otherwise noted: 25 °C, V<sub>D</sub> = 28 V, I<sub>DQ</sub> = 365 mA, Pulsed V<sub>D</sub>: PW = 100 us, DC = 10%

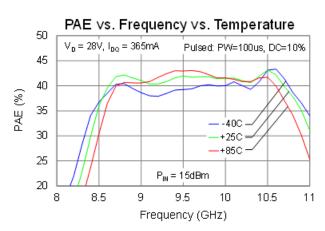








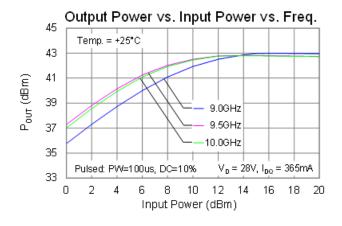


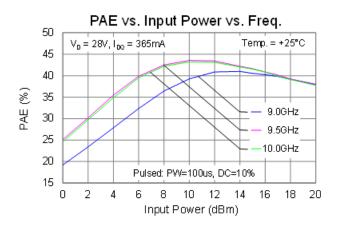


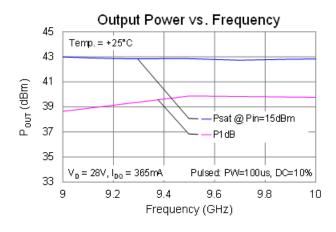


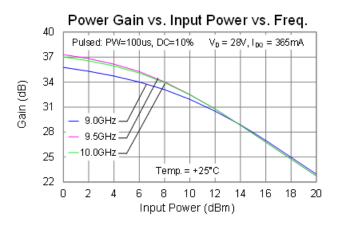
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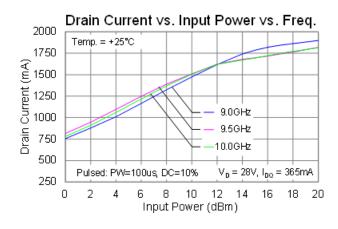
Test conditions unless otherwise noted: 25 °C, V<sub>D</sub> = 28 V, I<sub>DQ</sub> = 365 mA, Pulsed V<sub>D</sub>: PW = 100 us, DC = 10%

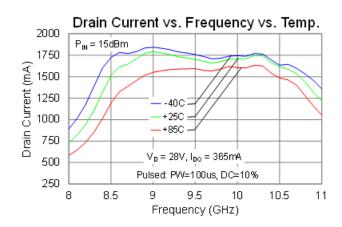






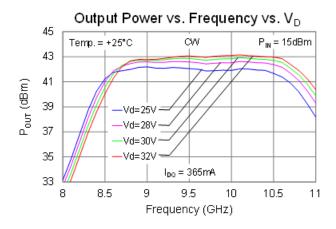


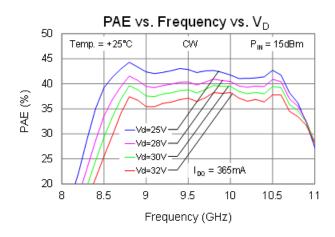


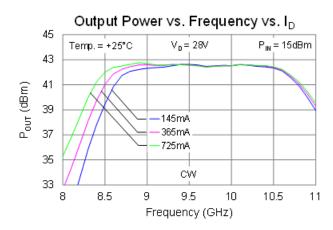


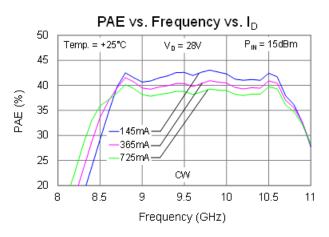


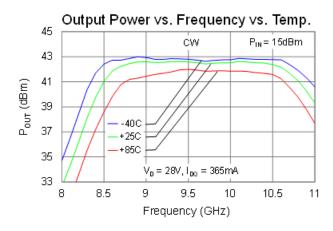
# Performance Plots - Large Signal (CW)

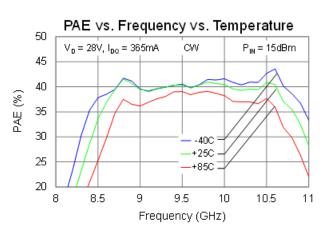






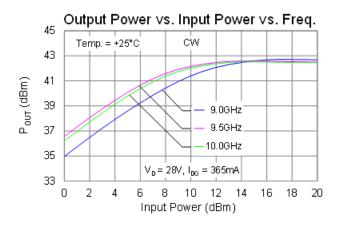


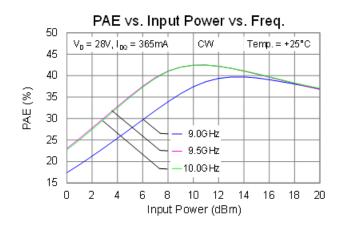


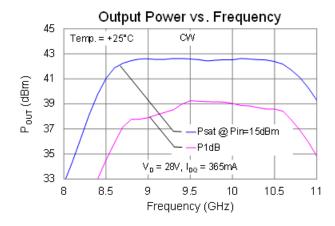


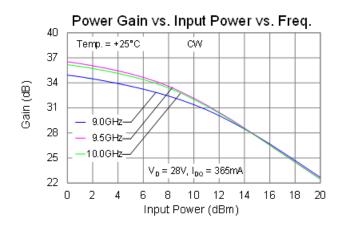


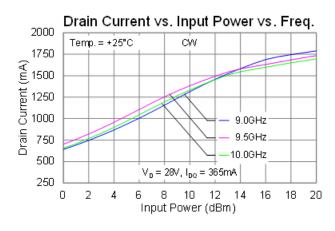
# Performance Plots - Large Signal (CW)

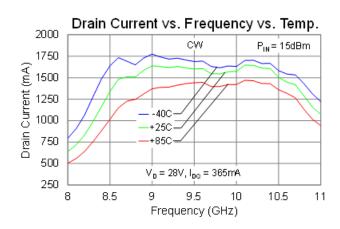






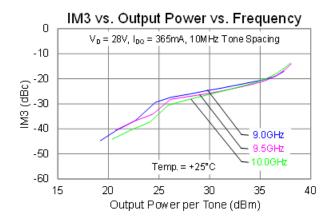


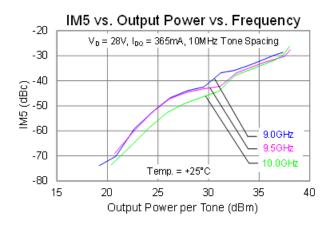


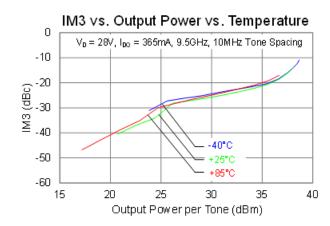


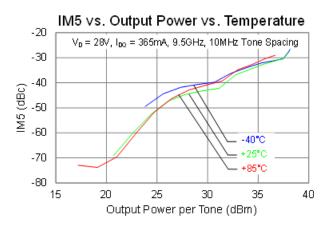


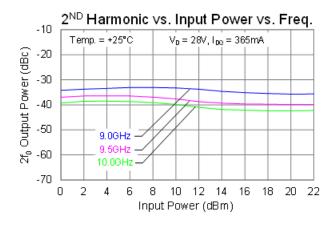
## Performance Plots - Linearity

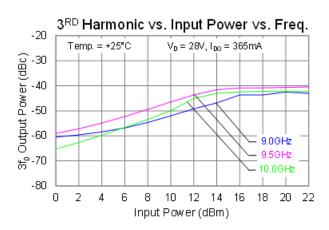






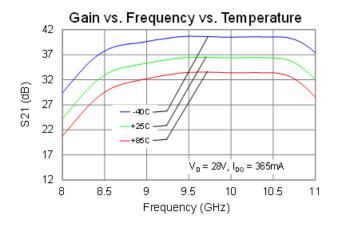


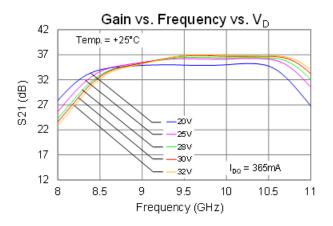


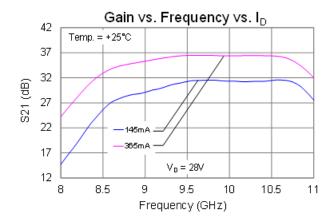


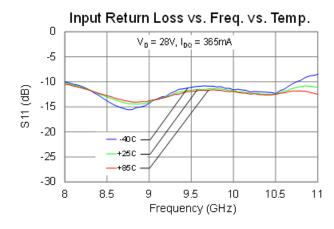


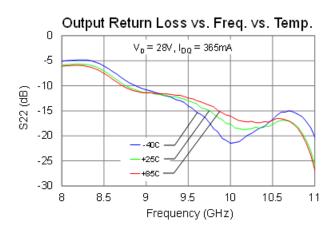
# Performance Plots - Small Signal













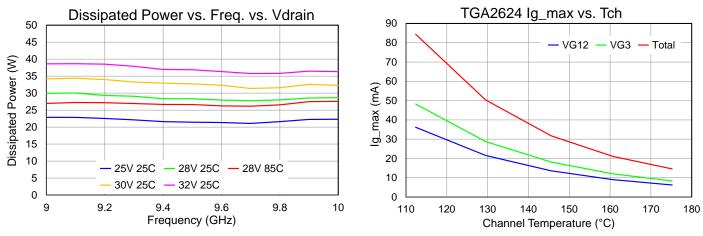
## **Thermal and Reliability Information**

Parameter	Test Conditions	Value	Units
Thermal Resistance ( $\theta_{JC}$ ) $^{(1)}$	$T_{\text{base}} = 85  ^{\circ}\text{C}$ , Pulsed $V_{\text{D}}$ : PW = 100 us, DC = 10%	2.372	°C/W
Channel Temperature, T <sub>CH</sub> (No RF) (2)	(Quiescent; no RF)	109	°C
Thermal Resistance (θ <sub>JC</sub> ) <sup>(1)</sup>	$T_{\text{base}} = 85  ^{\circ}\text{C}$ , Pulsed $V_D  V_D = 28  \text{V}$ , $I_{\text{Drive}} = 1.7  \text{A}$ ,	1.804	°C/W
Channel Temperature, T <sub>CH</sub> (Under RF) (2)	P <sub>IN</sub> = 17 dBm, P <sub>OUT</sub> = 43 dBm, P <sub>DISS</sub> = 29 W	137	°C
Thermal Resistance (θ <sub>JC</sub> ) <sup>(1)</sup>	T <sub>base</sub> = 85 °C, CW V <sub>D</sub> = 28 V, I <sub>Drive</sub> = 1.55 A, P <sub>IN</sub> =	2.596	°C/W
Channel Temperature, T <sub>CH</sub> (Under RF) (2)	17 dBm, P <sub>OUT</sub> = 42 dBm, P <sub>DISS</sub> = 28 W	158	°C

#### Notes:

- 1. Thermal resistance determined to the back of 40 mil CuMo carrier plate (85 °C) with eutectic die atatch
- 2. IR scan equivalent. Refer to the following document: <u>GaN Device Channel Temperature, Thermal Resistance, and Reliability</u> Estimates

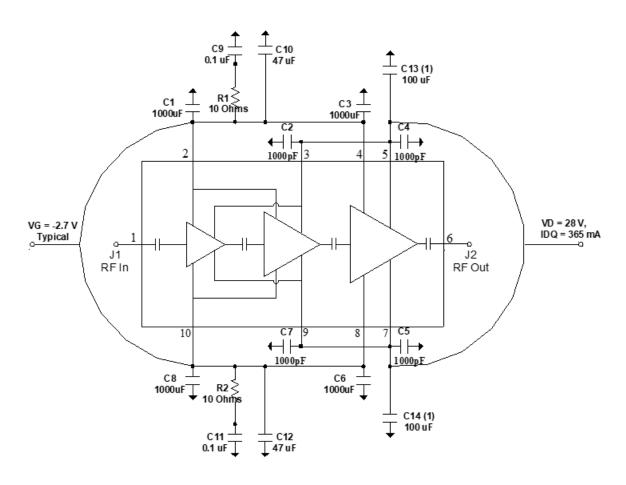
## **Dissipated Power and Maximum Gate Current**



Test conditions, unless otherwise noted:  $V_D = 28 \text{ V}$ ,  $I_{DQ} = 365 \text{ mA}$ ,  $T = +25 \,^{\circ}\text{C}$ ,  $P_{IN} = 17 \text{ dBm}$ 



# **Application Circuit**



(1) Remove 100 uF capacitors (C13, C14) for pulsed operation.

# **Bias-Up Procedure**

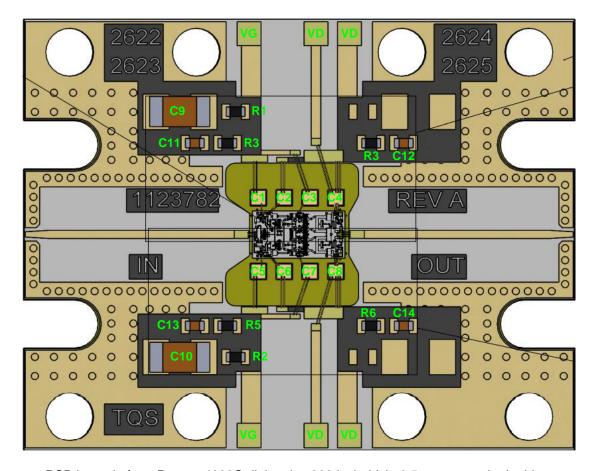
- 1. Set I<sub>D</sub> limit to 1900 mA, I<sub>G</sub> limit to 12 mA
- 2. Set V<sub>G</sub> to -5.0 V
- 3. Set V<sub>D</sub> +28 V
- 4. Adjust  $V_G$  more positive until  $I_{DQ} \approx 365$  mA
- 5. Apply RF signal

### **Bias-Down Procedure**

- 1. Turn off RF signal
- 2. Reduce  $V_G$  to -5.0 V. Ensure  $I_{DQ} \sim 0$  mA
- 4. Set  $V_D$  to 0 V
- 5. Turn off V<sub>D</sub> supply
- 6. Turn off V<sub>G</sub> supply



# **Evaluation Board (EVB) Layout Assembly**



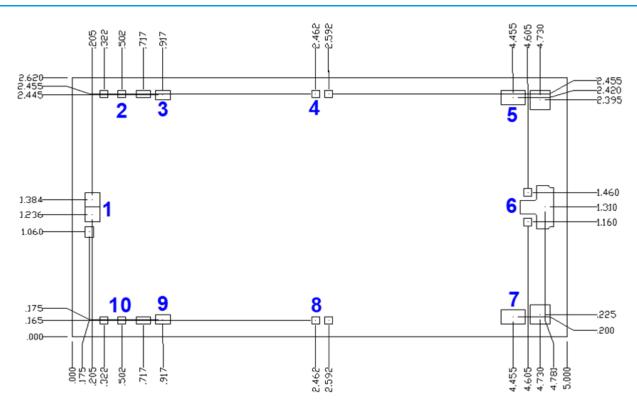
PCB is made from Rogers 4003C dielectric, .008 inch thick, 0.5 oz. copper both sides.

### **Bill of Materials**

Reference Des.	Value	Description	Manuf.	Part Number
C1,C2,C3,C4,C5,C6,C7,C8	1000 pF	CAP, 1000 pF, ±10% 50V, BORDER, SL	Various	
C11,C12,C13,C14	0.1 uF	CAP, 0.1 uF, 10%, 50V, X7R, 0402	Various	
C9,C10	10 uF	CAP, 10 uF, +/-10%, 25V, X5R, 1206	Various	
R1,R2	0 Ω	RES, 0 OHM, JMPR, 0402	Various	
R3,R4,R5,R6	10 Ω	RES, 10 OHM, 5%, 0.1W, 0402	Various	
J1, J2	2.92 mm	RF Connector (F), 2.92 mm	SW Microwave	1092-01A-5



### **Mechanical Information**



Dimensions are in mm
Thickness: 0.10
Die x, y size tolerance: ± 0.050
Ground is backside of die

# **Bond Pad Description**

Pad No.	Symbol	Size (um x um)	Description		
1	RF In	0.150 x 0.300	RF Input; matched to 50Ω; DC Blocked		
2, 8	V <sub>G1-2</sub>	0.080 x 0.080	Gate voltage 1-2, bias network is required; see Application Circuit on page 10 as an example.		
3, 9	V <sub>D1-2</sub>	0.150 x 0.100	Drain voltage 1-2, bias network is required; see Application Circle on page 10 as an example.		
4, 10	V <sub>G3</sub>	0.080 x 0.080	Gate voltage 3, bias network is required; see Application Circuit on page 10 as an example.		
5, 7	V <sub>D3</sub>	0.250 x 0.150	Drain voltage 3, bias network is required; see Application Circuit on page 10 as an example.		
6	RF Out	0.180 x 0.350	RF Output; matched to 50Ω; DC Blocked		



### 9-10 GHz 18 Watt GaN Power Amplifier

## **Assembly Notes**

Component placement and adhesive attachment assembly notes:

- · Vacuum pencils and/or vacuum collets are the preferred method of pick up.
- Air bridges must be avoided during placement.
- The force impact is critical during auto placement.

### Reflow process assembly notes:

- Use AuSn (80/20) solder and limit exposure to temperatures above 300 °C to 3-4 minutes, maximum.
- An alloy station or conveyor furnace with reducing atmosphere should be used.
- · Do not use any kind of flux.
- · Coefficient of thermal expansion matching is critical for long-term reliability.
- Devices must be stored in a dry nitrogen atmosphere.

#### Interconnect process assembly notes:

- Thermosonic ball bonding is the preferred interconnect technique.
- · Force, time, and ultrasonic are critical parameters.
- · Aluminum wire should not be used.
- Devices with small pad sizes should be bonded with 0.0007-inch wire.



### **Handling Precautions**

Parameter	Rating	Standard		Caution!
ESD – Human Body Model (HBM)	0B	JEDEC JESD22-A114	18	ESD-Sensitive Device

### **Solderability**

Use only AuSn (80/20) solder, and limit exposure to temperatures above 300 °C to 3-4 minutes, maximum.

## **RoHS Compliance**

This part is compliant with 2011/65/EU RoHS directive (Restrictions on the Use of Certain Hazardous Substances in Electrical and Electronic Equipment) as amended by Directive 2015/863/EU.

This product also has the following attributes:

- Lead Free
- Halogen Free (Chlorine, Bromine)
- Antimony Free
- TBBP-A (C<sub>15</sub>H<sub>12</sub>Br<sub>4</sub>O<sub>2</sub>) Free
- PFOS Free
- SVHC Free

#### **Contact Information**

For the latest specifications, additional product information, worldwide sales and distribution locations:

Web: <u>www.qorvo.com</u>
Tel: 1-844-890-8163

Email: customer.support@gorvo.com

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